



# The 22nd Asian Test Symposium (ATS'13)

Yilan, Taiwan, 18-21 Nov. 2013

<http://bug.ee.ntu.edu.tw/ATS2013>

## Call For Participation

Early bird discount by Oct. 25, 2013

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The Asian Test Symposium (ATS) provides an open forum for researchers and industrial practitioners from all countries of the world, especially from Asia, to exchange innovative ideas on system, board, and device testing with design, manufacturing and field consideration in mind.

### Keynote

*Test Data Analytics - from Mathematical Tools to Applications*  
Kwang-Ting (Tim) Cheng, University of California, Santa Barbara

### Invited Speeches

*New Approaches to Improving Quality and Accelerating Yield Ramp to Meet Process Technology Disruptions*

Wu-Tung Cheng, Chief Scientist and Test Research Director, Mentor Graphics

*Wide I/O and 3D-IC Testing (tentative)*

William Wu Shen, Design Methodology Division, TSMC Ltd

### Full-Day and Embedded Tutorials

*Statistical Adaptive Test Methods Targeting "Zero Defect" IC Quality and Reliability*

Adit D. Singh, Auburn University

*Testing TSV-Based 3D Stacked ICs*

Krishnendu Chakrabarty, Duke University

*Data Mining in Test - Principles and Practices*

Li-C Wang, University of California, Santa Barbara

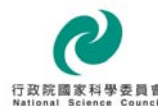
*Software Testing*

Farn Wang, National Taiwan University

### Vendor Session: New Test Technologies & Roadmap

Janusz Rajski, Mentor Graphics

Andy Hughes, Cadence



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